

August 2016

FCB110N65F

N-Channel SuperFET[®] II FRFET[®] MOSFET 650 V, 35 A, 110 m Ω

Features

- 700 V @T_J = 150°C
- Typ. $R_{DS(on)} = 96 \text{ m}\Omega \text{ (Typ.)}$
- Ultra Low Gate Charge (Typ. $Q_g = 98 \text{ nC}$)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 464 pF)
- · 100% Avalanche Tested
- · RoHS Compliant

Applications

- Telecom/Server Power Supplies Solar Inverters
- · Computing Power Supplies
- · FPD TV Power/Lighting

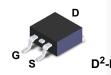
Description

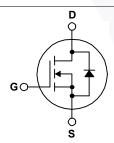
SuperFET® II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance.

SuperFET® II FRFET® MOSFET combines a faster and more rugged intrinsic body diode performance with fast switching,

aimed at achieving better reliability and efficiency especially in resonant switching applications.

SuperFET[®] II FRFET[®] is very suitable for the switching power applications such as server/telecom power, Solar inverter, FPD TV power, computing power, lighting and industrial power applications.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		Parameter		FCB110N65F	Unit
V _{DSS}	Drain to Source Voltage			650	V
	Cata ta Carras Valtaria	- DC		±20	V
V_{GSS}	Gate to Source Voltage	- AC		±30	V
I _D	Desir Comment	- Continuous (T _C = 25°C)	//	35	^
	Drain Current	- Continuous (T _C = 100°C)		24	A
I _{DM}	Drain Current	- Pulsed	(Note 1)	105	Α
E _{AS}	Single Pulsed Avalanche Ene	rgy	(Note 2)	809	mJ
I _{AR}	Avalanche Current		(Note 1)	8	Α
E _{AR}	Repetitive Avalanche Energy		(Note 1)	3.57	mJ
dv/dt	MOSFET dv/dt (Note 3)		100	1//	
dv/dt	Peak Diode Recovery dv/dt	Peak Diode Recovery dv/dt		50	V/ns
D.	D D: : #	(T _C = 25°C)		357	W
P_{D}	Power Dissipation	- Derate Above 25°C		2.86	W/°C
T _J , T _{STG}	Operating and Storage Tempe	erature Range		-55 to +150	°C
T _L	Maximum Lead Temperature 1/8" from Case for 5 Seconds	•		300	°C

Thermal Characteristics

Symbol	Parameter	FCB110N65F	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.35	
D	Thermal Resistance, Junction to Ambient (Mimimum Pad of 2-oz copper), Max.	62.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (1 in ² Pad of 2-oz copper), Max.	40	

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Tape Width
FCB110N65F	FCB110N65F	D ² -PAK	Tape and Reel	330 mm	24 mm	800 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charact	eristics					
D\/	Drain to Source Breakdown Voltage	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}, T_J = 25^{\circ}\text{C}$	650	-	-	V
BV _{DSS}	Diaili to Source Breakdown voltage	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}, T_J = 150^{\circ}\text{C}$	700	-	-	V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 10 mA, Referenced to 25°C	-	0.72	-	V/°C
1	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{GS} = 0 V	-	-	10	^
IDSS	Zelo Gate voltage Dialii Cultelit	$V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	110	-	μΑ
I_{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 3.5 \text{ mA}$	3	-	5	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 17.5 \text{ A}$	-	96	110	mΩ
9 _{FS}	Forward Transconductance	V _{DS} = 20 V, I _D = 17.5 A	-	30	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	100 1/ 1/ 01/	-	3680	4895	pF
Coss	Output Capacitance	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	-	110	145	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/12	-\	0.65	-	pF
Coss	Output Capacitance	V _{DS} = 380 V, V _{GS} = 0 V, f = 1 MHz	- \	65	-	pF
Coss eff.	Effective Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V	- \	464	-	pF
Q _{g(tot)}	Total Gate Charge at 10V	V _{DS} = 380 V, I _D = 17.5 A,	-	98	145	nC
Q_{gs}	Gate to Source Gate Charge	V _{GS} = 10 V	-	20	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	(Note 4)	-	43	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	0.7	-	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		-	31	72	ns
t _r		$V_{DD} = 380 \text{ V}, I_D = 17.5 \text{ A},$	-/	21	52	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_g = 4.7 Ω	-	89	188	ns
t _f	Turn-Off Fall Time	(Note 4)	/ -	5.7	21	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	35	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			-	100	Α
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{SD} = 17.5 \text{ A}$	-	-	1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{SD} = 17.5 \text{ A},$	-	133	- ,	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	0.67	-	μС

Notes:

- 1. Repetitive rating: pulse width limited by maximum junction temperature.
- 2. I_{AS} = 8 A, R_{G} = 25 Ω , starting T_{J} = 25°C.
- 3. I $_{SD} \leq$ 17.5 A, di/dt \leq 200 A/µs, V $_{DD} \leq$ 380 V, starting T $_{J}$ = 25°C.
- ${\bf 4.} \ Essentially \ independent \ of \ operating \ temperature \ typical \ characteristics.$

Typical Performance Characteristics

Figure 1. On-Region Characteristics

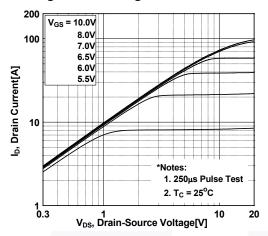


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

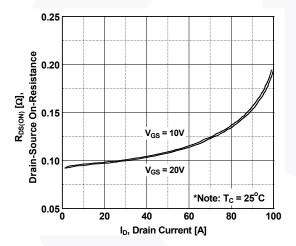


Figure 5. Capacitance Characteristics

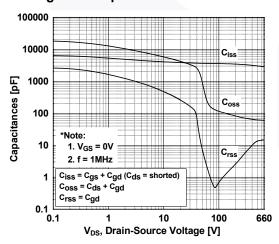


Figure 2. Transfer Characteristics

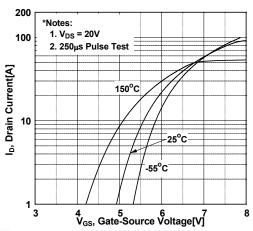


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

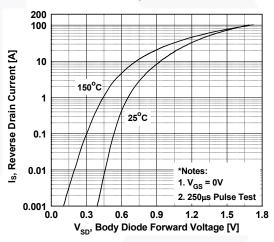
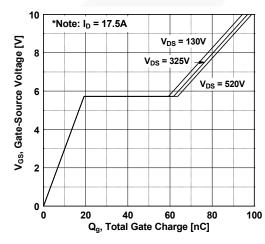


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

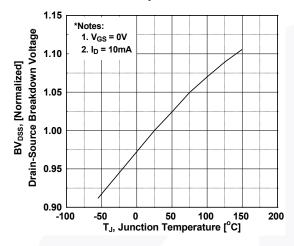


Figure 9. Maximum Safe Operating Area

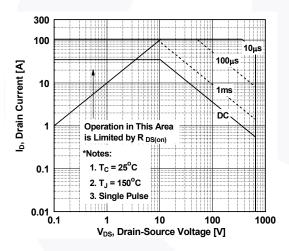


Figure 11. Eoss vs. Drain to Source Voltage Switching Capability

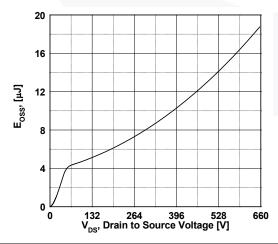


Figure 8. On-Resistance Variation vs. Temperature

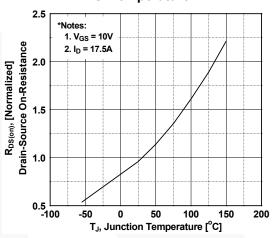
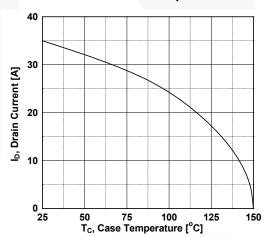
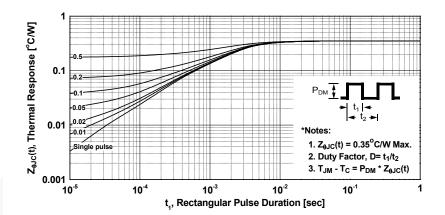


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 12. Transient Thermal Response Curve



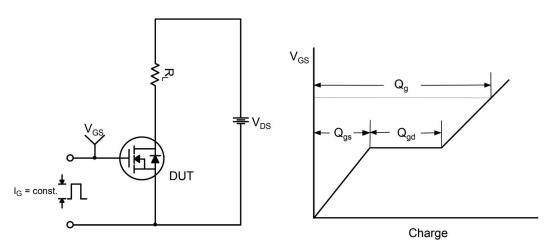


Figure 13. Gate Charge Test Circuit & Waveform

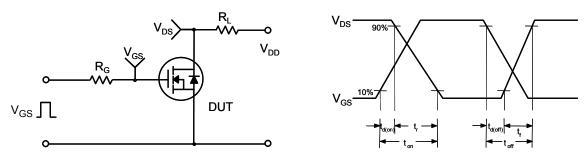


Figure 14. Resistive Switching Test Circuit & Waveforms

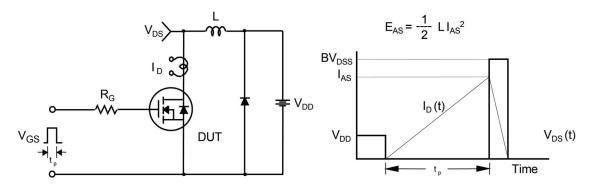
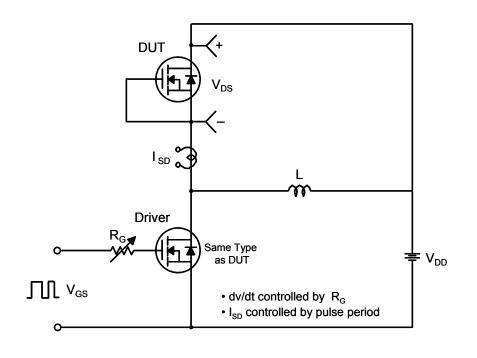


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms



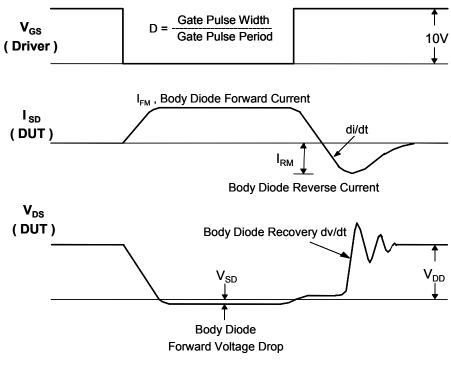
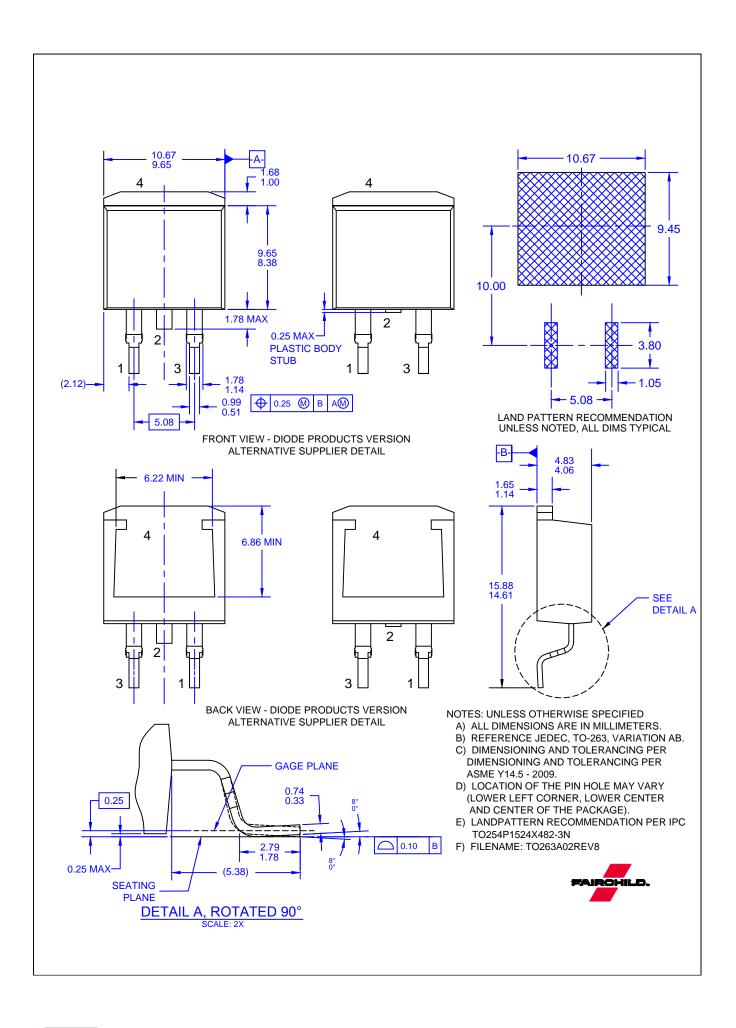


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms



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